

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of
Abdurrahman Sezginer et al.

Application No.: 10/074,561

Filed: February 12, 2002

For: OVERLAY ALIGNMENT METROLOGY
USING DIFFRACTION GRATINGS



Group Art Unit: 2877

Examiner: Zandra V. Smith

**RESPONSE TO OFFICE ACTION
MAILED DECEMBER 22, 2003**

121 Spear Street, Suite 290
San Francisco, CA 94105
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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited
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Box 1450, Alexandria, VA 22313-1450 on March 3, 2004.
STALLMAN & POLLOCK LLP

Dated: 03/3 /2004

By:

Georgia K. Stith
Georgia K. Stith

Sir:

In response to the Office Action mailed December 22, 2003, please amend the above-identified application as follows:

Amendment to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 13 of this paper.

03/10/2004 EAREGAY1 00000078 10074561

01 FC:2201

344.00 OP

Atty Docket No.: TWI-30400